

## Power MOSFET

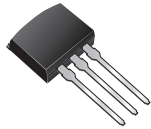
PRODUCT SUMMARY		
$V_{DS}$ (V)	- 60	
$R_{DS(on)}$ ( $\Omega$ )	$V_{GS} = -10$ V	0.28
$Q_g$ (Max.) (nC)	19	
$Q_{gs}$ (nC)	5.4	
$Q_{gd}$ (nC)	11	
Configuration	Single	

### FEATURES

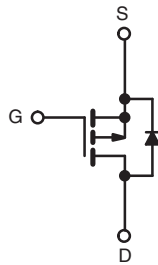
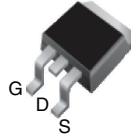
- Advanced Process Technology
- Surface Mount (IRF9Z24S/SiHF9Z24S)
- Low-Profile Through-Hole (IRF9Z24L/SiHF9Z24L)
- 175 °C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead (Pb)-free Available



I<sup>2</sup>PAK (TO-262)



D<sup>2</sup>PAK (TO-263)



P-Channel MOSFET

### DESCRIPTION

Third generation Power MOSFETs from Vishay utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D<sup>2</sup>PAK is a surface mount power package capable of accommodating die size up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D<sup>2</sup>PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

The through-hole version (IR9Z24L/SiH9Z24L) is available for low-profile applications.

### ORDERING INFORMATION

Package	D <sup>2</sup> PAK (TO-263)	D <sup>2</sup> PAK (TO-263)	D <sup>2</sup> PAK (TO-263)	I <sup>2</sup> PAK (TO-262)
Lead (Pb)-free	IRF9Z24SPbF	IRF9Z24STRLPbF <sup>a</sup>	IRF9Z24STRRPbF <sup>a</sup>	IRF9Z24LPbF
	SiHF9Z24S-E3	SiHF9Z24STL-E3 <sup>a</sup>	SiHF9Z24STR-E3 <sup>a</sup>	SiHF9Z24L-E3
SnPb	IRF9Z24S	IRF9Z24STRL <sup>a</sup>	IRF9Z24STRR <sup>a</sup>	IRF9Z24L
	SiHF9Z24S	SiHF9Z24STL <sup>a</sup>	SiHF9Z24STR <sup>a</sup>	SiHF9Z24L

**Note**

a. See device orientation.

### ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	$V_{DS}$	- 60	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$		
Continuous Drain Current <sup>e</sup>	$V_{GS}$ at - 10 V	$T_C = 25$ °C	- 11	A
		$T_C = 100$ °C	- 7.7	
Pulsed Drain Current <sup>a, e</sup>	$I_{DM}$	- 44		
Linear Derating Factor		0.40	W/°C	
Single Pulse Avalanche Energy <sup>b, e</sup>	$E_{AS}$	240	mJ	
Repetitive Avalanche Current <sup>a</sup>	$I_{AR}$	- 11	A	
Repetitive Avalanche Energy <sup>a</sup>	$E_{AR}$	6.0	mJ	

\* Pb containing terminations are not RoHS compliant, exemptions may apply

# IRF9Z24S, IRF9Z24L, SiHF9Z24S, SiHF9Z24L

Vishay Siliconix



ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$ , unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Maximum Power Dissipation	$T_A = 25\text{ }^\circ\text{C}$	$P_D$	3.7	W
	$T_C = 25\text{ }^\circ\text{C}$		60	W
Peak Diode Recovery $dV/dt^c$		$dV/dt$	- 4.5	V/ns
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	- 55 to + 175	$^\circ\text{C}$
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>	


## Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = -25\text{ V}$ , starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $L = 2.3\text{ mH}$ ,  $R_G = 25\text{ }\Omega$ ,  $I_{AS} = -11\text{ A}$  (see fig. 12).
- $I_{SD} \leq -11\text{ A}$ ,  $dI/dt \leq 140\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 175\text{ }^\circ\text{C}$ .
- 1.6 mm from case.
- Uses IRF9Z24/SiHF9Z24 data and test conditions.

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	$R_{thJA}$	-	-	40	$^\circ\text{C}/\text{W}$
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	-	2.5	

## Note

- When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$ , unless otherwise noted							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX. UNIT	
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0\text{ V}$ , $I_D = -250\text{ }\mu\text{A}$		- 60	-	- V	
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25\text{ }^\circ\text{C}$ , $I_D = -1\text{ mA}^c$		-	- 0.056	- $^\circ\text{C}/\text{V}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = -250\text{ }\mu\text{A}$		- 2.0	-	- 4.0 V	
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20\text{ V}$		-	-	$\pm 100\text{ nA}$	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -60\text{ V}$ , $V_{GS} = 0\text{ V}$		-	-	- 100 $\mu\text{A}$	
		$V_{DS} = -48\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$		-	-	- 500 $\mu\text{A}$	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = -10\text{ V}$	$I_D = -6.6\text{ A}^b$	-	-	0.28 $\Omega$	
Forward Transconductance	$g_{fs}$	$V_{DS} = -25\text{ V}$ , $I_D = -6.6\text{ A}^c$		1.4	-	- S	
<b>Dynamic</b>							
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}$ , $V_{DS} = -25\text{ V}$ , $f = 1.0\text{ MHz}$ , see fig. 5 <sup>c</sup>		-	570	-	
Output Capacitance	$C_{oss}$			-	360	-	pF
Reverse Transfer Capacitance	$C_{rss}$			-	65	-	
Total Gate Charge	$Q_g$	$V_{GS} = -10\text{ V}$	$I_D = -11\text{ A}$ , $V_{DS} = -480\text{ V}$ , see fig. 6 and 13 <sup>b, c</sup>	-	-	19	
Gate-Source Charge	$Q_{gs}$			-	-	5.4	nC
Gate-Drain Charge	$Q_{gd}$			-	-	11	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -30\text{ V}$ , $I_D = -11\text{ A}$ , $R_G = 18\text{ }\Omega$ , $R_D = 2.5\text{ }\Omega$ , see fig. 10 <sup>b</sup>		-	13	-	
Rise Time	$t_r$			-	68	-	ns
Turn-Off Delay Time	$t_{d(off)}$			-	15	-	
Fall Time	$t_f$			-	29	-	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode 		-	-	- 11	
Pulsed Diode Forward Current <sup>a</sup>	$I_{SM}$			-	-	- 44	A
Body Diode Voltage	$V_{SD}$	$T_J = 25\text{ }^\circ\text{C}$ , $I_S = -11\text{ A}$ , $V_{GS} = 0\text{ V}^b$		-	-	- 6.3 V	

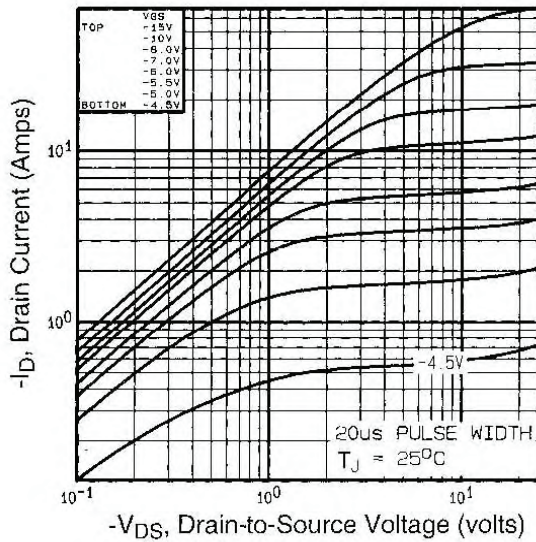


SPECIFICATIONS $T_J = 25^\circ\text{C}$ , unless otherwise noted						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
<b>Drain-Source Body Diode Characteristics</b>						
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ\text{C}$ , $I_F = -11\text{ A}$ , $dI/dt = 100\text{ A}/\mu\text{s}^{b,c}$	-	100	200	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$		-	320	640	nC
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )				

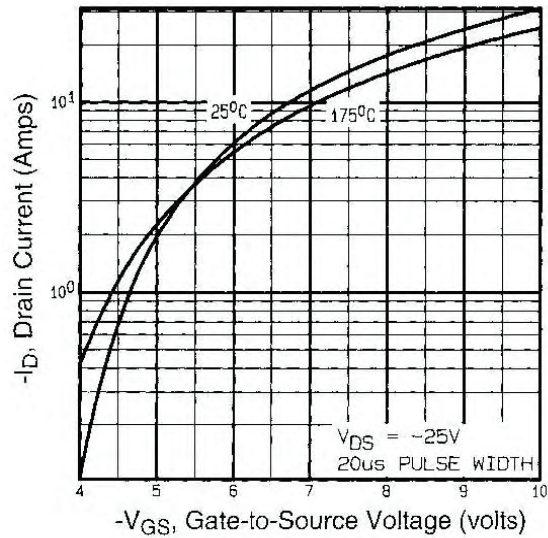
**Notes**

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300\ \mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- c. Uses IRF9Z24/SiHF9Z24 data and test conditions.

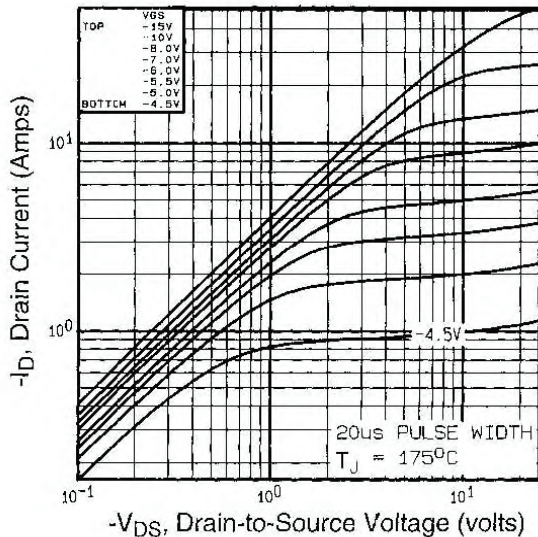
**TYPICAL CHARACTERISTICS**  $25^\circ\text{C}$ , unless otherwise noted



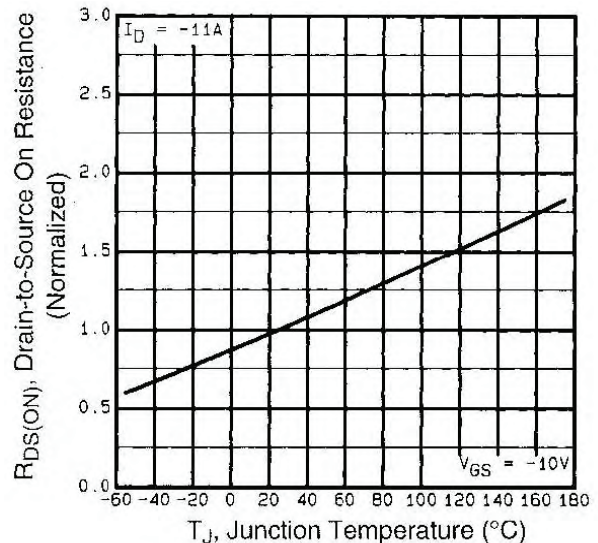
**Fig. 1 - Typical Output Characteristics**



**Fig. 3 - Typical Transfer Characteristics**



**Fig. 2 - Typical Output Characteristics**



**Fig. 4 - Normalized On-Resistance vs. Temperature**

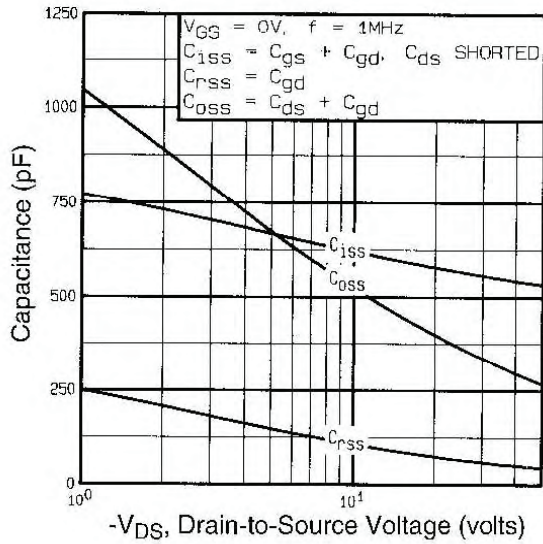


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

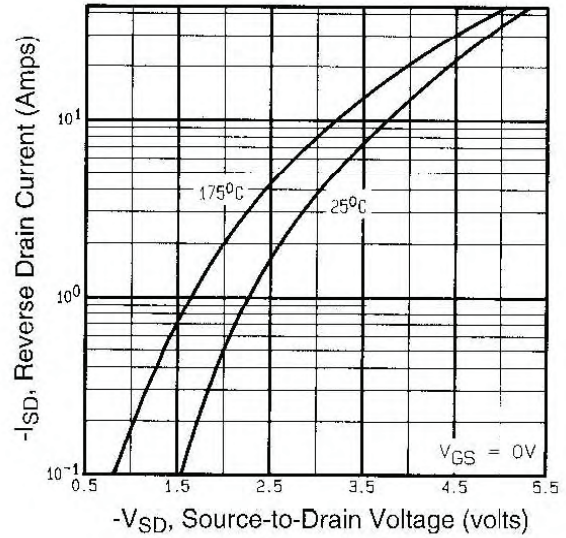


Fig. 7 - Typical Source-Drain Diode Forward Voltage

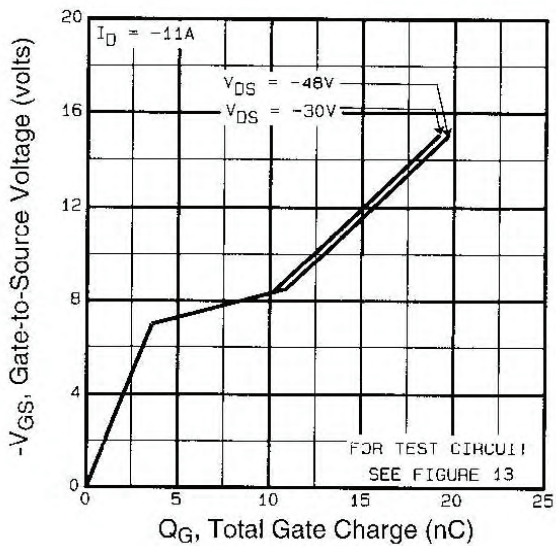


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

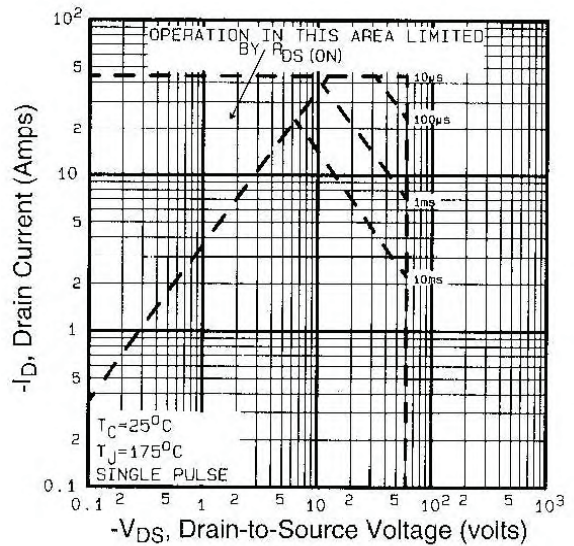


Fig. 8 - Maximum Safe Operating Area

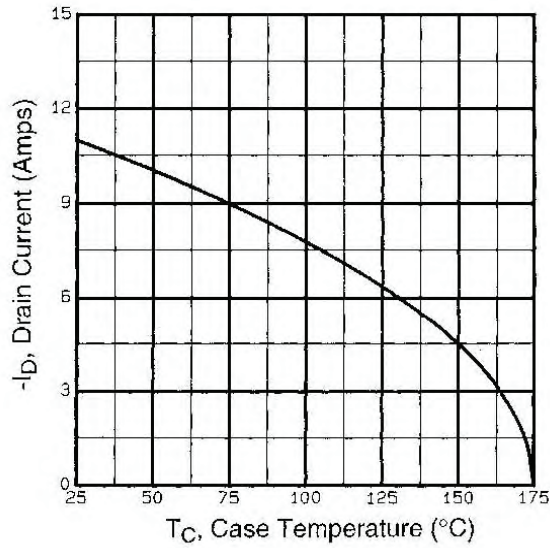


Fig. 9 - Maximum Drain Current vs. Case Temperature

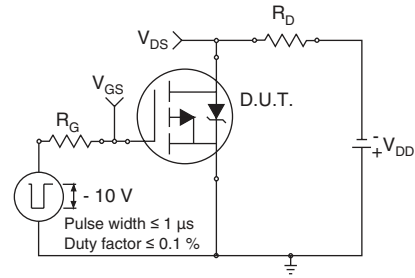


Fig. 10a - Switching Time Test Circuit

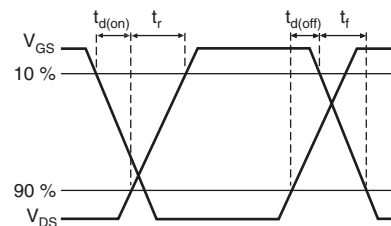


Fig. 10b - Switching Time Waveforms

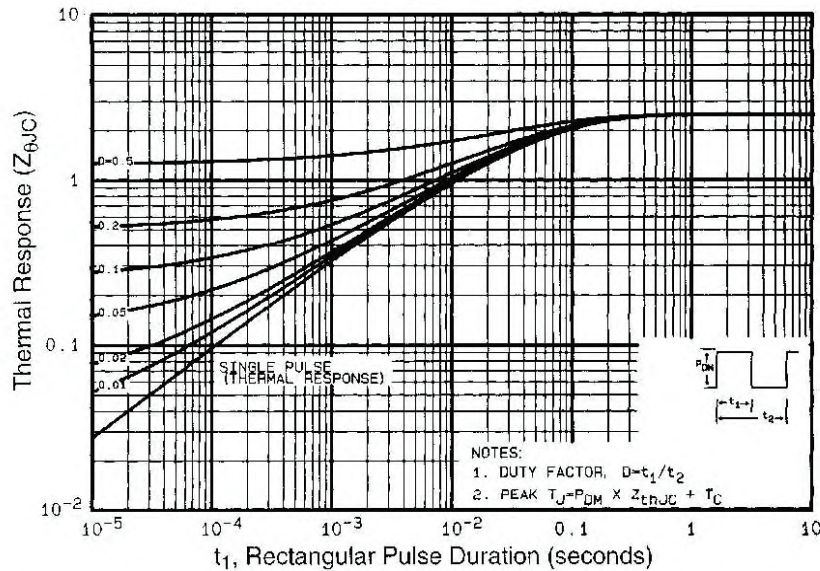


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

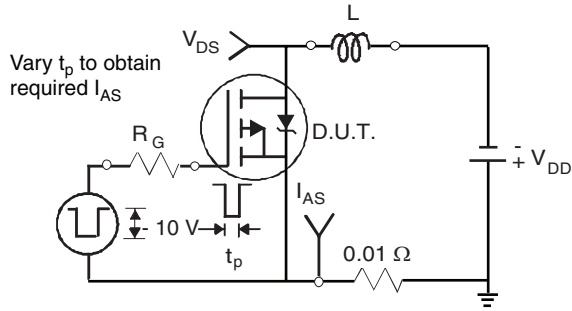


Fig. 12a - Unclamped Inductive Test Circuit

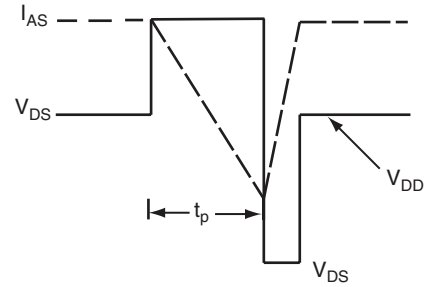


Fig. 12b - Unclamped Inductive Waveforms

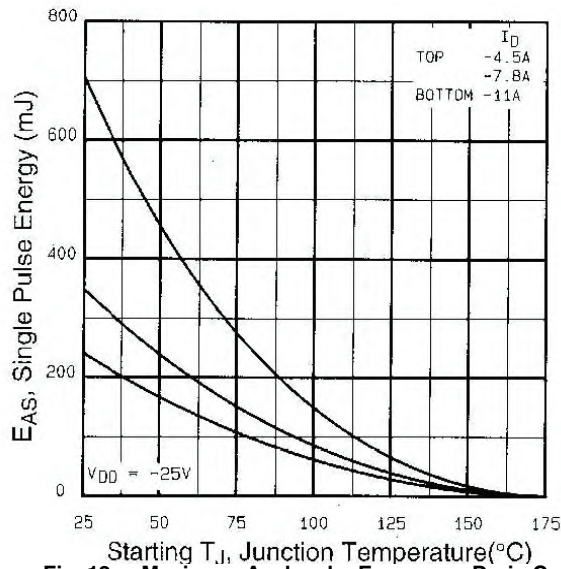


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

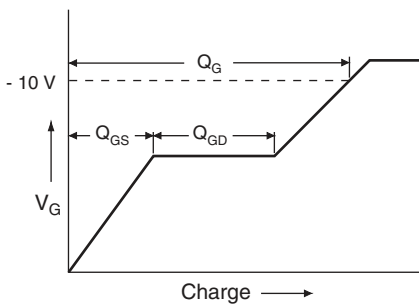


Fig. 13a - Basic Gate Charge Waveform

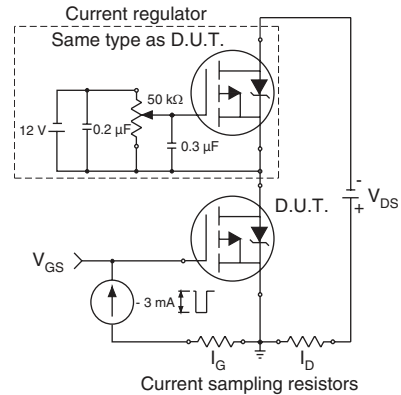
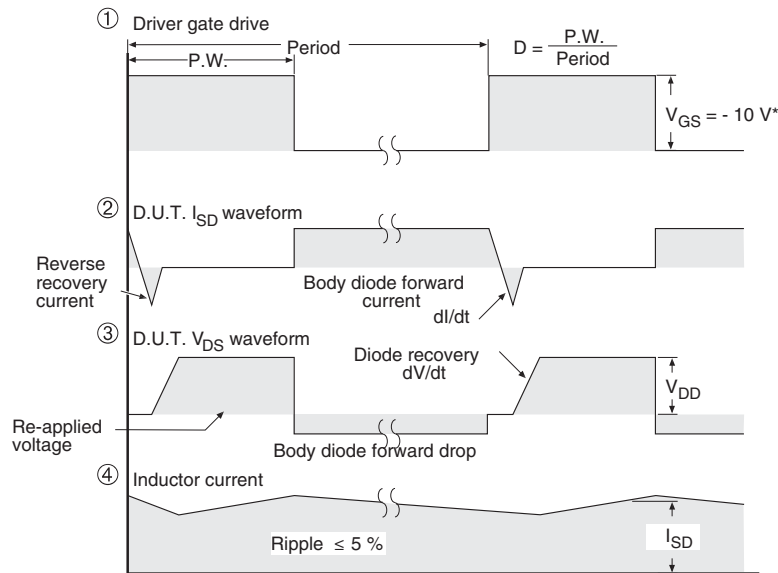
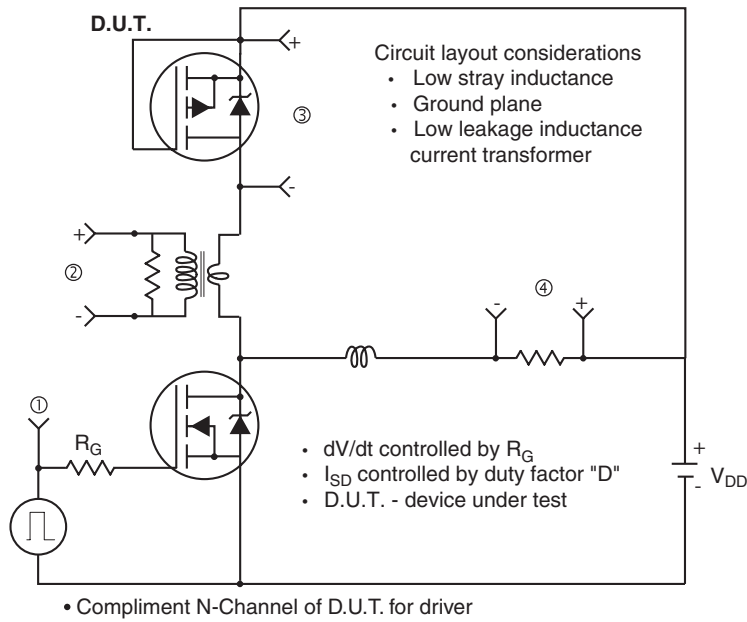


Fig. 13b - Gate Charge Test Circuit

## Peak Diode Recovery $dV/dt$ Test Circuit



\*  $V_{GS} = -5\text{ V}$  for logic level and  $-3\text{ V}$  drive devices

**Fig. 14 - For P-Channel**

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <http://www.vishay.com/ppg?91091>.



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